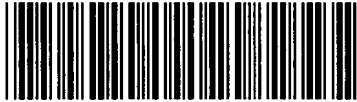


Search Notes

Application/Control No.

10/522,577

Examiner

Chau N. Nguyen

Applicant(s)/Patent under
Reexamination

TAKAHASHI ET AL.

Art Unit

2831

SEARCHED

Class	Subclass	Date	Examiner
174	106R	12/16/2005	CN
	108		
174	36	9/27/2006	CN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
see print out		9/28/2007	CN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text	12/16/2005	CN